ATTY DOCKET NO. SERIAL NO. 13931 unassigned INFORMATION DISCLOSURE CITATION APPLICANT(S) Kenji Yamanishi, et al (Use several sheets if necessary) FILING DATE GROUP herewith unassign **U.S. PATENT DOCUMENTS** FILLING DAT FYAMINER CLASS DOCUMENT NUMBER DATE NAME SUBCLASS INITIAL IF APPROPRIATE FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YES . (Including Author, Title, Date, Pertinent Pages, Etc.) OTHER DOCUMENTS Publication "Combining Data Mining and Machine Learning for Effective Fraud Detection", Proceedings of Al Approaches to Fraud Detection and Risk Management, by Tom Fawcell and Foster Provost, pp. 14-19, 1997. "Intrusion Detection with Neural Networks", by J. Ryan, M. Lin and R. Milkkulainen, Proceedings of AI Approaches to Fraud Detection and Risk Management, pp. 72-77, 1997. "Detecting Celliular Fraud Using Adaptive Prototypes", by P. Burge and J. Shawe-Taylor, Proceedings of Al Approaches to Fraud Detection and Risk Management, pp 9-13, 1997.

EXAMINER

ayal Sharon

DATE CONSIDERED

"Maximum Likelihood fromIncomplete Data via the EM Algorithm", by A.P. Dempster, N.M. Laird and D.B. Ribin, Journal of the Royal Statistical Society, B. 39(1), pp. 1-38, 1977.

5/14/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449)

P09C/REV03

Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE \$

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

ATTY DOCKET NO.

SERIAL NO.

APPLICANT(S) Kenji Yamanishi, et al

GROUP

FILING DATE herewith

unassigned.

U.S.	PATENT	DOCU	MENTS

		U.	S. PATENT DOCUMENTS			e mercane manifestation
'EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
					,	
						and the same of the same of
					.,	
`						مان المان الما المان المان ال
		FORE	IGN PATENT DOCUMENTS			- 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION:
					•	TES , NO
					`-	
				·		ا الله الله الله الله الله الله الله ال
<u>.</u>	OTHER DOCUME	NTS (Includin	g Author. Title. Date. Pertine	nt Pages, Etc.)	- 95	
	O THE TOO DINK		g Author, Title, Date, Pertine d by the Maximum-Entropy Prin			

Vol. 63, pp. 403-409, 1990. ayul

EXAMINER

agal Sharron

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449) P09C/REV03

Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE

PAGE

, -					Docket Number (Optional)		Application Nu	nmber	
				,	13931		(09/675,637	•
\Qu.		ATION DISCLOSURE		,	Applicant(s)				
/	,~,	Several succes if how	essary)	1		Cenji YAMA	NISHI, et. al.		
SEP 2	2 2003	<u></u>)		,	Filing Date		Group Art Unit		
12		<u>\$ </u>			September 29,	2000	<u> </u>	2123	
CAT A THAT	_ugt	*/	U.S	S. PATENT	T DOCUMENTS				
*EXAMINER	REP	DOCUMENT NUMBER	DATE	T	Name	CLASS	SUBCLASS	PILLE	IG DATE
INITIAL	<u></u>						8080		IG DATE ROPRIATE
					7			 	
	 '					<u></u> '			
i	,	•				['			٠,
	+		 	+		 	· · · · · · · · · · · · · · · · · · ·	 	
						1 2		1	•
	·			1			RECE	MED	/
	<u> </u>					I I	I .	1	
	1			T		1	367 % W	2003	
	 	 		+		l Te d	SEP 2 4 hnology C	hoter 91f	Δ
	'	1			,	1	filliology C,	و د ۱۳۱۵	סל
	 			+			 		
	'					1 1	1		
									
	<u>'</u>	<u> </u>	<u></u>	<u> </u>			<u> </u>		
		·· -	FORE	JGN PATE	ENT DOCUMENTS				
[REP	The second standard of the second sec		T				TRANSL	LATION
<u> </u>	Mas .	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	YES	NO
ayel		6-325009	11/25/94	Japar	n				
,									
					-				
		OTHER	DOCUMENTS (Including A	Author, Title, Date, Pertinent I	Pages, Etc.)			
					ce due to Mixel in Ca		ification	Tina F	
agail		Algorithm and Its	Improvemen	ıt", Vol.	. 37, No. 1, pp. 39-4	8, (Jan. 19	1881110au01. 96).	. USINg L.	M
		Ikno Yonemoto, f	at al "An O	n-line E	Estimation Algorithm	of Drohal	Lility Densi	L. Enneti	
Bun 8	1 1	Using Information	n Criterion",	The Inst	titute of Electronics,	I OI FIUUGU Informati	Ality Densi	ly runcu	on ··
ayan.	1 1	Engineers. Techni	ical Report of	FIFICE	, PRMU98-174 (199	<u>. Illivillians</u>	190.104	Municau	ion
	 							= * * /1/	
April		Hang Li, vi. ai.,	Jocument Ch	assilica:	tion Using a Finite N	Aixture ivid	odel", pp. 3	i7-44, (19	197).
EXAMINER		- 46			DATE CONSIDERED				
	apel					5/14/	04		
EXAMINER: I	nitial If c	itation considered, whether	r or not citation is in	in conform/	nance with MPEP 609; Draw	line through ci	tation if not in	conformance	and not

Form PTO-A820 (also form PTO-1449)

P09A/REV04

Patent and Trademark Office' U.S. DEPARTMENT OF COMMERCE

INFORMATION	DISCLOSURE	CITATION

(Use several sheets if necessary)

ATTY DOCKET NO.

APPLICANT(S) Kenji Yamanishi, et al

LING	DAI	E	
			herewith

GROUP

unassigned

U.S.	PATENT	DOCUMENTS

		U.S. PA	TENT DOCUMENTS	-		
*EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
					3.	
			· · · · · · · · · · · · · · · · · · ·			
						,
	·					Line about
			<u>.</u>			
<u> </u>	· · ·	FOREIGN	PATENT DOCUMENTS			Service S
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
			*		3 2 2 2 2	TES NO
		1 -				
	OTHER DOCUME	INTS (Including A	uthor, Title, Date, Pertine	ent Pages, Etc.)		
	"Self-Organization of N		the Maximum-Entropy Pri		•	ogical Cybernetics,

Vol. 63, pp. 403-409, 1990.

EXAMINER

ayal Sharron

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449) P09C/REV03

Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE